IS	sue	CI	ass	SITIC	ation

09/692,100

Examiner

Kim-Kwok CHU

Applicant(s)/Patent	unde
Reexamination	

TESHIMA ET AL.

Art Unit

2653

ISSUE CLASSIFICATION									
ORIGINAL			CROSS REFERENCE(S)						
CLASS	SUBCLASS	CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)						
369	47.1	369	47.19 47.22 47.43						
INTERNATIO	NAL CLASSIFICATION	386	52	55	68	69	91	98	
611	8 2710								
H044	1 5193		,						
	1								
	1					, ,			
	1								
Kim-Kwok CHU (Assistant Examiner) (Date)			VILLIAM KORZUCH SUPERVISORY PATENT EXAMINER			Total Claims Allowed: 21			
MN511-28-05			TECHNOLOGY CENTER 2600 (Primary Examiner) (Date)			O. Print C	G. łaim(s)	O.G. Print Fig.	
(Legal Instruments Examiner) (Date)						1	8	3 & 4	

Claims renu	aims renumbered in the same order as presented by applicant				☐ T.D.	☐ R.1.47
Final	Final	Final	Final	Final	Final	Final Original
7 0	31	61	91	121	151	181
12'	32	62	92	122	152	182
2 3	33	63	93	123	153	183
3 4	34	64	94	124	154	184
4 5	35	65	95	125	155	185
5 6	36	66	96	126	156	186
6 7	37	67	97	127	157	187
6 8	38	68	98	128	158	188
<b>Q</b> 9	39	69	99	129	159	189
9 10	40	70	100	130	160	190
[0] 11	41	71	101	131	161	191
11 12	42	72	102	132	162	192
12 13	43	73	103	133	163	193
14 (14) 15 15	44	74	104	134	164	194
15 15	45	75	105	135	165	195
<b>/b</b> 16	46	76	106	136	166	196
17 17	47	77	107	137	167	197
12 (18)	48	78	108	138	168	198
j <b>G</b> 19	49	79	109	139	169	199
20 20	50	80	110	140	170	200
<b>2</b> 21	51	81	111	141	171	201
13 22	52	82	112	142	172	202
23	53	83	113	143	173	203
24	54	84	114	144	174	204
25	55	85	115	145	175	205
26	56	86	116	146	176	206
27	57	87	117	147	177	207
28	58	88	118	148	178	208
29	59	89	119	149	179	209
30	60	90	120	150	180	210